

TOSHIMICHI KITAOKA et al.

3

[object; characterized in that] object, said matching material [has] having an acoustic impedance matched to an acoustic impedance of said test object.

2. (Amended) A focus type longitudinal wave ultrasonic probe for polymer material inspection comprising a curved piezoelectric element, and a matching material having an input end surface in close contact with a concave surface of said 5 curved piezoelectric element[,] and an output end surface for fitting to a surface of a polymer material acting as a test [object; characterized in that] object, said matching material [has] having an acoustic impedance matched to an acoustic impedance of said curved piezoelectric element.

3. (Amended) A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in claim 1, [comprising a curved piezoelectric element, and a matching material having an input end surface in close contact 5 with a concave surface of said curved piezoelectric element, and an output end surface for fitting to a surface of a polymer material acting as a test object;

characterized in that] wherein:

said matching material has an acoustic impedance 10 matched to an acoustic impedance of said test object; and

TOSHIMICHI KITAOKA et al.

4

said matching material has an acoustic impedance matched to an acoustic impedance of said curved piezoelectric element.

4. (Amended) A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in [any one of claims 1 - 3, characterized in that] claim 1, wherein said curved piezoelectric element comprises a polymer  
5 piezoelectric material.

5. (Amended) A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in [any one of claims 1 - 4, characterized in that] claim 1, wherein the acoustic impedance of said matching material varies from a  
5 value matching the acoustic impedance of said curved piezoelectric element toward a value matching the acoustic impedance of said test object, with respect to a direction of propagation from said input end surface to [the] said output end surface of a longitudinal ultrasonic wave launched by said curved  
10 piezoelectric element.

6. (Amended) A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in [any one of claims 1 - 5 characterized in that] claim 1, wherein

TOSHIMICHI KITACKA et al.

5

said matching material is divided into a first matching material  
5 and a second matching material, said first matching material  
having one end surface [thereof] formed as said input end  
surface[,] and the other end surface formed as a first transition  
end surface, said second matching material having one end surface  
[thereof] formed as said output end surface[,] and the other end  
10 surface formed as a second transition end surface for close  
contact with said first transition end surface, said first  
transition end surface having an acoustic impedance matched to  
an acoustic impedance of said second transition end surface.

7. (Amended) A focus type longitudinal wave  
ultrasonic probe for polymer material inspection as defined in  
claim 6, [characterized in that] wherein said second matching  
material is attachable to and detachable from said first matching  
5 material.

8. (Amended) [In a] A flaw evaluating apparatus for  
an ultrasonic flaw detecting apparatus for transmitting  
ultrasonic wave to a polymer material acting as a test object,  
and receiving echoes returning [therefrom;] therefrom, the flaw  
5 evaluating apparatus [for an ultrasonic flaw detection apparatus  
is characterized by] comprising a first gate circuit for  
generating a first gate for an echo from a predetermined

TOSHIMICHI KITAOKA et al.

6

reflection source in said test object, a second gate circuit for generating a second gate for flaw detection in a position of a 10 predetermined time delay from said first echo, a first evaluating circuit for determining that a flaw has been detected when an amplitude of said first echo exceeds a predetermined level, and a second evaluating circuit for determining that a flaw has been detected when an echo occurs at said second gate.

9. (Amended) A flaw evaluating apparatus as defined in claim 8, [characterized in that] wherein said second gate circuit is operable to vary an interval time between said first echo and said second gate following a variation in sound velocity 5 in said test object.

10. (Amended) A flaw evaluating apparatus for an ultrasonic flaw detection apparatus as defined in claim 8, [characterized in that] wherein said first gate circuit is operable to vary an interval time between a surface echo and said 5 first gate following a variation in sound velocity in said test object.

11. (Amended) A flaw evaluating apparatus for an ultrasonic flaw detection apparatus as defined in claim 9 [or 10, characterized in that] wherein said variation in sound velocity

TOSHIMICHI KITAOKA et al.

7

in said test object is determined by measuring an interval time  
5 between echoes from two predetermined reflection sources in said  
test object.

--12. A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in claim 2, wherein said curved piezoelectric element comprises a polymer piezoelectric material.

13. A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in claim 3, wherein said curved piezoelectric element comprises a polymer piezoelectric material.

14. A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in claim 2, wherein the acoustic impedance of said matching material varies from a value matching the acoustic impedance of said curved 5 piezoelectric element toward a value matching the acoustic impedance of said test object, with respect to a direction of propagation from said input end surface to said output end surface of a longitudinal ultrasonic wave launched by said curved piezoelectric element.

TOSHIMICHI KITAOKA et al.

8

15. A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in claim 3, wherein the acoustic impedance of said matching material varies from a value matching the acoustic impedance of said curved piezoelectric element toward a value matching the acoustic impedance of said test object, with respect to a direction of propagation from said input end surface to said output end surface of a longitudinal ultrasonic wave launched by said curved piezoelectric element.

16. A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in claim 4, wherein the acoustic impedance of said matching material varies from a value matching the acoustic impedance of said curved piezoelectric element toward a value matching the acoustic impedance of said test object, with respect to a direction of propagation from said input end surface to said output end surface of a longitudinal ultrasonic wave launched by said curved piezoelectric element.

17. A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in claim 2, wherein said matching material is divided into a first matching material and a second matching material, said first matching material

TOSHIMICHI KITAOKA et al.

9

5 having one end surface formed as said input end surface and the other end surface formed as a first transition end surface, said second matching material having one end surface formed as said output end surface and the other end surface formed as a second transition end surface for close contact with said first  
10 transition end surface, said first transition end surface having an acoustic impedance matched to an acoustic impedance of said second transition end surface.

18. A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in claim 3, wherein said matching material is divided into a first matching material and a second matching material, said first matching material  
5 having one end surface formed as said input end surface and the other end surface formed as a first transition end surface, said second matching material having one end surface formed as said output end surface and the other end surface formed as a second transition end surface for close contact with said first  
10 transition end surface, said first transition end surface having an acoustic impedance matched to an acoustic impedance of said second transition end surface.

TOSHIMICHI KITAOKA et al.

10

19. A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in claim 4, wherein said matching material is divided into a first matching material and a second matching material, said first matching material 5 having one end surface formed as said input end surface and the other end surface formed as a first transition end surface, said second matching material having one end surface formed as said output end surface and the other end surface formed as a second transition end surface for close contact with said first 10 transition end surface, said first transition end surface having an acoustic impedance matched to an acoustic impedance of said second transition end surface.

20. A focus type longitudinal wave ultrasonic probe for polymer material inspection as defined in claim 5, wherein said matching material is divided into a first matching material and a second matching material, said first matching material 5 having one end surface formed as said input end surface and the other end surface formed as a first transition end surface, said second matching material having one end surface formed as said output end surface and the other end surface formed as a second transition end surface for close contact with said first

TOSHIMICHI KITAOKA et al.

11

10 transition end surface, said first transition end surface having an acoustic impedance matched to an acoustic impedance of said second transition end surface.

21. A flaw evaluating apparatus for an ultrasonic flaw detection apparatus as defined in claim 10, wherein said variation in sound velocity in said test object is determined by measuring an interval time between echoes from two predetermined  
5 reflection sources in said test object.--

IN THE ABSTRACT:

Please delete the Abstract of the Invention as currently on file and substitute therefor the new Abstract Of The Invention included herewith as a separately typed page.

REMARKS

The specification has been amended to place the application in conformance with standard United States Patent practice.

Claims 1-11 have been amended to eliminate the multiple dependencies and to bring the claims into conformance with standard United States Patent practice. New claims 12-21 have been added to more fully define the invention.